Welcome to SIMS XV Manchester 2005

On behalf of the SIMSXV Organising Committee it is a great pleasure to welcome you to the University of Manchester to participate in the 15th International Conference on Secondary Ion Mass Spectrometry. As well as being the first time that a SIMS International Conference has come to the UK, our conference is one of the first international conferences to be held in the University of Manchester that was created in 2004 by bringing together UMIST and The Victoria University of Manchester. It is the largest single site university in the UK. As a conference that explores the cutting edge of our science we should feel at home because research is at the heart of this University. It has a distinguished history in research, innovation and enterprise stretching back over 75 years. No fewer than 23 former staff and students have gone on to become Nobel prizewinners. Major scientific advances at Manchester include Rutherford's work leading to the splitting of the atom and the development of the world's first modern computer.

It is a very exciting time for SIMS and we have sought to highlight this in our choice of the invited speakers and in some novel aspects of the programme. There are new challenges in semiconductor materials analysis as new materials are being explored. This is reflected in the focused session on advanced dielectric materials organised by Joe Bennett. The development of cluster ion beams offers very significant new opportunities in complex materials analysis. The session organised by Nick Winograd and sponsored by IONTOF will explore the sputtering phenomena and the new analytical rules that may emerge. The one-day Symposium organised by Mark Dowsett on the exploitation of SIMS in the fields of Archæometry, Cosmochemistry and Geology brings some historically important applications of SIMS together with very new developments in the contrasting areas of space science and the preservation of ancient artefacts. The exploitation of SIMS' ability to probe complex chemistry at high spatial resolution in its application to the study of biological tissue and cellular materials will be explored in depth during the Discussion Day sponsored by ULVAC-Phi. We are particularly pleased that we are able to welcome a number of biologists and users of other mass spectral techniques to participate in this Discussion. However, perusal of the rest of the programme, posters and orals, shows that exciting developments are not limited to these areas. We have a real feast that I hope all will enjoy.

We are very honoured to welcome the Nobel Laureate, Professor Sir Harry Kroto FRS to give our plenary lecture on Monday. The great potential offered by cluster ion beams as exemplified by C_{60}^+ makes his lecture on the further insights into fullerene and nanotube formation particularly interesting. We are also very pleased to welcome Professor Simon Gaskell who is the Associate Vice-President for Research here in Manchester. He has an enormous reputation in the application of mass spectrometry to the biosciences. As SIMS seeks to contribute to biological studies his plenary lecture on Wednesday will, I am sure, be listened to with great interest.

This series of International Conferences was founded by Professor Alfred Benninghoven in Münster in 1975. The International Committee that has guided the very successful series of meetings since then has decided it is time to stand down. It is therefore with some anticipation that we look forward to the inauguration of a new International Committee during this Conference.

Manchester has a great industrial history. It is now very successfully reinventing itself as a post-industrial centre of science, technology, sport, culture and commerce. We hope the social programme will help you to get a feel for the past and sample some of the new things on offer. The conference dinner on Wednesday will be in the Town Hall built at the height of Manchester's industrial power.

We hope the meeting and your stay in Manchester will be up to your hopes and expectations. If you have any questions or problems do not hesitate to ask for help at the Registration Desk, from one of the student helpers in their blue polo shirts or from a member of the Organising Committee.

John Vickerman, Chair
Ian Gilmore, Co-Chair

Monday 12th September			
Session 1 – C16			
08:40		**Opening Address:** **Professor Dame Nancy Rothwell DBE, FRS, Vice President for Research, The University of Manchester** **Professor Alfred Benninghoven, Chair of the International Committee** **Professor John Vickerman, Chair of the SIMSXV Committee**	
09:00	**FUN2-I-Mo-A01**	**Atoms, Clusters, and Photons: Energetic Probes for Mass Spectrometry**	**Barbara Garrison**
09:40	FUN2-O-Mo-A02	Secondary Ion Yield Enhancement due to Cluster Ion Bombardment: A Surprise?	Klaus Wittmaack
10:00	FUN2-O-Mo-A03	Energy and angular distributions of secondary ions in the sputtering of gold by swift Aun clusters. Emission mechanisms	Serge Della-Negra
10:20	FUN2-O-Mo-A04	Effect of Molecular Binding Energy on Sputtering of Thin Organic Overlayers by keV Ga And C60 Bombardment	Zbigniew Postawa
10:40		Coffee	
11:00	**FUN2-I-Mo-A05**	**A fundamental review of organic ion emission using cluster ion beams**	**Andreas Wucher**
11:40	FUN2-O-Mo-A06	Applications of a Bismuth-Cluster Ion Gun in Inorganic Surface Analysis and Depth Profiling	Felix Kollmer
12:00	FUN2-O-Mo-A07	Sputtering of Amorphous Ice Induced by C60 and Au3 Clusters	Michael F Russo Jr
12:20	FUN2-O-Mo-A08	Molecular Ion Emission from Single Large Cluster Impacts	Stanislav V Verkhoturov
12:40	FUN2-O-Mo-A09	Stretching the limits of static SIMS with C60+	Arnaud Delcorte
13:00		Lunch	
14:00	**Plenary-Mo-A10**	**Some New Insights in to the Mechanisms of Fullerene and Nanotube Formation**	**Professor Sir Harry Kroto FRS**
15:00	CLU-O-Mo-A11	Molecular depth profiling with cluster ion source	Juan Cheng
15:20	CLU-O-Mo-A12	Temperature-Controlled Depth Profiling in Polymeric Biomaterials using Cluster Secondary Ion Mass Spectrometry (SIMS)	Christine Mahoney
15:40		Coffee	
16:00	CLU-O-Mo-A13	Using Polyatomic Primary Ions to Probe Amino Acids in Water Ice	Xavier A Conlan
16:20	CLU-O-Mo-A14	Chemical effects in C60 irradiation of polymers	Antonio Licciardello
16:40	CLU-O-Mo-A15	Molecular Depth Profiling of Organic and Biological Materials	John S Fletcher
17:00	CLU-O-Mo-A16	Probing Thin Overlayers With Variable Energy / Cluster Ion Beams	Alan Spool
Session 2 – C2			
09:00	**FUN1-I-Mo-B01**	**The limitations of SIMS in nanoscale technologies : quantitative near-surface and interfacial analysis of complex systems**	**Wilfried Vandervorst**
09:40	FUN1-O-Mo-B02	Ionization probability of sputtered particles as a function of their energy	Yuriy Kudriavtsev
10:00	FUN1-O-Mo-B03	Detection of Molecular Hydrogen Anions H2-, D2-, H3- and D3-	Hubert Gnaser
10:20	FUN1-O-Mo-B04	Sputtering and Desorption Processes at Low-Energy Ion Bombardment of Single Crystal Surfaces	Sirojiddin E Rahmatov
10:40		Coffee	

11:00	FUN1-O-Mo-B05	Sputtering of Mixed Clusters from a NiAl Surface	Bruce V King
11:20	FUN1-O-Mo-B06	Quantitative fundamental studies in SIMS using O18 implant standards	Peter Williams
11:40	FUN1-O-Mo-B07	Atomic Scale Modifications to a Silicon Sample during SIMS Analysis	Michael Wiedenbeck
12:00	FUN1-O-Mo-B08	Correlating the angular variation of the sputter yield with surface oxygen concentration during O2+ bombardment of Ge.	Tom Janssens
12:20	FUN1-O-Mo-B09	Processes active in group IB secondary ion formation/survival: Measurements of work function and electronic structure	Paul van der Heide
12:40	FUN1-O-Mo-B10	Statistical model for evaluating the relative contribution of different Sik+ bond states to the ionisation probability of Si+ sputtered from SiOx	Klaus Wittmaack
13:00		Lunch	
14:00	**Plenary-Mo-A10**	**Some New Insights in to the Mechanisms of Fullerene and Nanotube Formation**	**Professor Sir Harry Kroto FRS**
15:00	QUA-O-Mo-B11	SIMS Quantification of Binary Alloys and Composition Depth Profiling of Multilayers Using a Buckminsterfullerene (C60) Ion	Kyung J Kim
15:20	QUA-O-Mo-B12	Quantitative interpretation of the TOFSIMS decay data for the analysis of layer closure by ALD	Wilfried Vandervorst
15:40		Coffee	
16:00	QUA-O-Mo-B13	Activities of SIMS Standardization in ISO/TC 201/SC6	Yoshikazu Homma
16:20	QUA-O-Mo-B14	Important increase of negative secondary ion sensitivity during SIMS analysis by neutral cesium deposition	Patrick Philipp
16:40	QUA-O-Mo-B15	Study of the Pd-Rh interdiffusion by ToF-SIMS, RBS and PIXE: nature of the sputtered atom and ionization probability	Laurent Houssiau
17:00	QUA-O-Mo-B16	The peculiarities of secondary negative ions emission under Cs bombardment in a presence of oxygen	Alexander Merkulov
Poster Session 1, 17:20 – 19:00 – C15/B1			
	FUN-P-Mo-P01	Static SIMS - Results of a VAMAS Interlaboratory and the Protocol for a New Study	Felicia M Green
	FUN-P-Mo-P02	Strong composition-dependent variation of MCs+ sensitivity factors in TiOx and GeOx (x < 2) films	Hubert Gnaser
	FUN-P-Mo-P03	Surface roughness effects in quantitative analysis of ToF-SIMS data	Jennifer Armitage
	FUN-P-Mo-P04	Accurate SIMS depth profiling for high concentration samples	Susumu Saito
	FUN-P-Mo-P05	Chemical derivatization technique in ToF-SIMS for quantification analysis of surface amine groups	Tae G Lee
	FUN-P-Mo-P06	SIMS Quantification of Matrix and Impurity Species in AlxGa1-xN	Fred A Stevie
	FUN-P-Mo-P07	Round-Robin Study of Arsenic Implant Dose Measurement in Silicon by SIMS	David Simons
	FUN-P-Mo-P08	PLA-PMMA blends : a study by XPS and ToF SIMS	Damien Cossement
	QUA-P-Mo-P09	Sputter Yields in Diamond Bombarded by Ultra Low Energy Ions	Berta Guzman de la Mata
	QUA-P-Mo-P10	Comparative study of negative cluster emission in sputtering of Si, Ge, and their oxides	Michele Perego
	QUA-P-Mo-P11	Non-Linearity and Non-Additivity of Secondary Ion Emission of Metals and Semiconductors under Cluster Ion Bombardment	Sergey N Morozov
	QUA P-Mo-P12	Comparison of detection efficiencies of negatively charged gold-alkanethiolate-, gold-sulfur- and gold-clusters in ToF-SIMS	Sascha Sohn

	QUA-P-Mo-P13	Direct cluster emission and electron capture at sputtering of silicon under cesium ion bombardment	Bakhtiyar Atabaev
	QUA-P-Mo-P14	Energy distributions of atomic and molecular ions sputtered by C60+ projectiles	Arnaud Delcorte
	QUA-P-Mo-P15	Decay reactions of (SiO2)nO- clusters: dissociation energies and structures	Nariman Dzhemilev
	QUA-P-Mo-P16	Formation of atomic ions in fragmentation of sputtered clusters	Nariman Dzhemilev
	QUA-P-Mo-P17	Steady-state Cs surface concentration on Si and Ge after low energy Cs+ bombardment by SIMS	Ping Chen
	QUA-P-Mo-P18	AFM Study of the Sims Beam Induced Roughness in Monocrystalline Silicon in Presence of Initial Surface or Bulk Nanometric Sized Defects	Boubker Fares
	QUA-P-Mo-P19	Properties and Use of the Depth Resolution Function in Sims Analysis	J C Dupuy
	QUA-P-Mo-P20	Determination of energy dependent ionization probabilities for sputtered particles	Paul Mazarov
	QUA-P-Mo-P21	Transient affects active during secondary ion emission from Si and SiO2 surfaces under Cs+ primary ion impact	Paul van der Heide
	QUA-P-Mo-P22	Studies into the removal of SIMS transient affects in the analysis of Si wafers with Cs+ primary ions	Paul van der Heide
	QUA-P-Mo-P23	Modelling the negative ionisation of sputtered carbon atoms	Jorge Silva
	QUA-P-Mo-P24	Modeling the dissociation and ionization of a sputtered organic molecule	Vadim Solomko
	QUA-P-Mo-P25	Analysis of SIMS for LB Film due to the Thermal Decomposition using QMD Method	Nobuhiko Kato
	QUA-P-Mo-P26	XY+ bombardement / Cs° deposition: evolution of Cs surface concentration with respect to bombardment conditions by TRIDYN simulations	Patrick Philipp
	ACG-P-Mo-P27	uleSIMS characterization of silver reference surfaces	Vladimir Palitsin
	ACG-P-Mo-P28	Ion-Tof Analysis of Corroding Museum Glass	Sarah Fearn
	ACG-P-Mo-P29	ToF-SIMS applied to historical archaeology in the Alps	Rana N S Sodhi
	ACG-P-Mo-P30	Obsidian Hydration Dating from Sims H+ Profiling Based on Saturated Surface (Ss) Layer	Ioannis Liritzis
	ACG-P-Mo-P31	SIMS Depth Profiling for Obsidian Hydration Dating	Steven Novak
	ACG-P-Mo-P32	Automated Ion Imaging with the NanoSIMS Ion Microprobe	Elmar Groener
	ACG-P-Mo-P33	Measurement of 26Al Diffusion in Single Crystalline 2/1-Mullite by SIMS Depth Profiling	Peter Fielitz
	ACG-P-Mo-P34	SIMS Quantification of Very Low H2O Contents	Dieter Rhede
	ACG-P-Mo-P35	Preferential Oxidation of Chalcopyrite Surface Facets Characterized by ToF-SIMS and SEM	Frank Rutten
	ISO-P-Mo-P36	High Throughput Screening of Novel Oxide Conductors using SIMS	Sarah Fearn
	ISO-P-Mo-P37	Resonant Laser-SNMS of Boron for Analysis of Paleoceanographic Samples	Guido Vering
	CLU-P-Mo-P38	Secondary Ion Emission from Indium Sputtered by Gold-Cluster Projectiles	Sergey Morozov
	CLU-P-Mo-P39	Secondary Ion Emission from Silicon under Sim- and Aum- Cluster Ions Bombardment	Sergey Morozov
	CLU-P-Mo-P40	Cluster sputtering of silicon and silicon carbide under subkeV polyatomic SF5 ion bombardment	Bakhtiyar Atabaev
	CLU-P-Mo-P41	Secondary Ion Emission from Phthalocyanine Films with Gold-Cluster Projectiles	Sergey Morozov
	CLU-P-Mo-P42	Molecular Dynamics Simulations to Explore Chemical Reactions and Topography Formation in the Bombardment of Si(100) with C60	Kristin Krantzman

	CLU-P-Mo-P43	Evaluation of secondary ion yield enhancement from polymer material by using TOF-SIMS equipped with a gold cluster ion source	Kenichi Aimoto
	CLU-P-Mo-P44	Molecular Dynamics Study of Particle Emission by Reactive Cluster Ion Impact	Takaaki Aoki
	CLU-P-Mo-P45	High-intensity Si cluster ion emission from a silicon target bombarded with large Ar cluster ions	Satoshi Ninomiya
	CLU-P-Mo-P46	Characterization of Drug-Eluting Stent (DES) Materials with Cluster Secondary Ion Mass Spectrometry (SIMS)	Christine Mahoney
	CLU-P-Mo-P47	Performance of a C60+ Ion Source on a Dynamic SIMS Instrument	Albert Fahey
	CLU-P-Mo-P48	TOF-SIMS Imaging of OLED using a Au Cluster Ion Beam	Scott Bryan
	CLU-P-Mo-P49	Au-Analyte Adducts Resulting from Single Massive Gold Cluster Impacts	George Hager
	CLU-P-Mo-P50	Organic SIMS with single massive gold projectile: Ion yield enhancement by silver metallization	Christelle Guillermier
	CLU-P-Mo-P51	Kinetic energy distributions of neutral In and In2 sputtered by polyatomic ion bombardment	Andrey Samartsev
	CLU-P-Mo-P52	Mass spectra and ionization probabilities of Indium species sputtered by atomic and polyatomic ion bombardment.	Andrey Samartsev
	CLU-P-Mo-P53	Study of Polymer Fragmentation using Polyatomic Primary Ions	Xavier Conlan
	CLU-P-Mo-P54	Influence of Primary Ion Species on the Secondary Cluster Ion Emission Process from SAMs of Hexadecanethiol on Gold	Markus Schröder
	BIO1-P-Mo-P55	Enhanced Peptide Molecular Imaging by Aqueous Droplet	Yohei Murayama
	BIO1-P-Mo-P56	TOF-SIMS analysis of fresh frozen, freeze-dried rat cerebellum	Håkan Nygren
	BIO1-P-Mo-P57	Cardiac cell and tissue analysis by gold cluster ion bombardment	Monika Aranyosiova
	BIO1-P-Mo-P58	Hair Dye distribution in human hair by ToF SIMS	Bo-Jung Chen
	BIO1-P-Mo-P59	Model Multilayer Structures for Three-Dimensional Cell Imaging	Joseph Kozole
	BIO1-P-Mo-P60	Is it possible to differentiate between intact and denatured adsorbed proteins without using recognising reactions?	Peggy Rossbach
	BIO1-P-Mo-P61	Competitive adsorption of proteins on polymers membranes studied by ToF-SIMS and PCA	Marie Henry
	BIO1-P-Mo-P62	Dynamic SIMS Analysis of Cryo-Prepared Biological and Geological Specimens	Michelle Dickinson
	BIO1-P-Mo-P63	Lipid Profiling of Prostate Cancer Cells Using ToF-SIMS	Matthew Baker
	BIO1-P-Mo-P64	Lipid and Sterol analysis of Candida albicans using TOF-SIMS	Bonnie Tyler
	BTC-P-Mo-P65	G-SIMS of Biodegradable Homo-Polyesters	Ryosuke Ogaki
	BTC-P-Mo-P66	Quantitative ToF-SIMS study of adsorbed proteins	Tae G Lee
	NAN-P-Mo-P67	Imaging, Spectra, and Chemometrics of ToF-SIMS of Alkyl Monolayers on Silicon, Germanium and Silicon Nitride made by Laser Activation, Chemomechanical	Matthew R Linford
	NAN-P-Mo-P68	RuO2/SiO2/Si and SiO2/porous Si/Si interfaces analysed by SIMS	Piotr Konarski
	NAN-P-Mo-P69	The SIMS investigation of structural effect of oxygen segregation on superplastic deformed nanobulk titanium surfaces	Bakhtiyar Atabaev
	NAN-P-Mo-P70	Supramolecular host-guest complexes base on	D Velic
	ORG1-P-Mo-P71	End group effect on surface and interfacial segregation in PS-PMMA blend thin films	Lekshmi Kailas

	ORG1-P-Mo-P72	Empirical evaluation of metal deposition for the S-SIMS analysis of organic compounds in thick samples	Roel De Mondt
	ORG1-P-Mo-P73	S-SIMS in advanced textile research: study of additives to tune the hydrophilic/hydrophobic properties of polypropylene films	Bart Boschmans
	ORG1-P-Mo-P74	S-SIMS analysis of plasma treated 'real life' polypropylene films	Bart Boschmans
	ORG1-P-Mo-P75	Surfactant Cationisation In ToF-SIMS Analysis	Mark Perkins
	ORG1-P-Mo-P76	TOF-SIMS investigation of the distribution of a cosmetic ingredient in the epidermis of the skin	Masayuki Okamoto
	ORG1-P-Mo-P77	Development of a highly sensitive analysis technique for surfactants by time-of-flight secondary ion mass spectrometry	Noriyuki Tanji
	ORG1-P-Mo-P78	Surface Characterization of Self Assembled Monolayers of Alkane Dithiols	Bonnie J Tyler
	DAT-P-Mo-P79	Application of Advanced Data Analysis Techniques in ToF-SIMS: Toward Faster Relevant Observations for Industrial Problem-Solving	Gregg E Potter
	DAT-P-Mo-P80	ToF – SIMS identification of diterpenes after chromatographic separation.	Andrej Oriňák
	MAT-P-Mo-P81	Examination of the Influence of Boron on the Microstructure and Properties of Low C Ferritic Steels using NanoSIMS and TEM	Shafiq Ahmed
	MAT-P-Mo-P82	Carbon analysis in steel microstructure	Didier Loison
	MAT-P-Mo-P83	SIMS Analysis of Nitrogen in Various Metals and ZnO	Yupu Li
19:00		Manufacturers Session – C16	
	Millbrook	The Millbrook Desktop MiniSIMS - New TOF Version Now Available	John Eccles
	ULVAC-PHI	New SIMS Developments from ULVAC-PHI	J Hammond
	Kratos	Surface analysis with high energy and spatial resolution XPS	Chris Blomfield
	ION-TOF	TOF.SIMS 5, Recent Developments and Applications	Markus Terhorst
	CAMECA	Recent developments in CAMECA SIMS. Part 1: magnetic sector instruments	Michel Schuhmacher
	CAMECA	Recent development in CAMECA SIMS. Part 2: quadrupole instruments	Hans Maul
	Cascade	Characterisation of Advanced Semiconductor Materials at Cascade Scientific	Chris Mulcahy
	Evans East	T^2 SIMS Replot Software: Everything You Ever Wanted From Replot Software But Were Too Afraid To Ask	Charles W Magee

Tuesday 13th September

Session 3 – C16

09:00	**ACG-I-Tu-A01**	**The geological ion microprobe: the first 25 years of dating zircons**	**William Compston**
09:40	**ACG-I-Tu-A02**	**Applications of SIMS to archaeometry and cultural heritage**	**Annemie Adriaens**
10:20	ACG-O-Tu-A03	The use of nanoSIMS to critically test claims of early (3.5 billion year old) life	Matt Kilburn
10:40		Coffee	
11:00	**ACG-I-Tu-A04**	**NanoSIMS: A new tool in cosmochemistry**	**Peter Hoppe**
11:40	ACG-O-Tu-A05	IDLE: (Interstellar Dust Laser Explorer), A New Instrument for Submicron Analyses of Stardust -	Ian Lyon

		Quantification in SIMS and Laser SNMS	
12:00	ACG-O-Tu-A06	Analyses of Micrometeorite Impact Features on the Salyut 7 Russian Space Station Titanium Tank	Virginie Jantou
12:20	ACG-O-Tu-A07	Application of the 182Hf-182W chronometer to eucrite zircon and initial solar 182Hf abundance – a multicollector SIMS approach	Martin Whitehouse
12:40	ACG-O-Tu-A08	Surface analysis of ancient glass artefacts with ToF-SIMS: a novel tool for provenancing?	Frank Rutten
13:00		Lunch	
14:00	**ACG-I-Tu-A09**	**SIMS Analysis of Ancient Materials**	**David S McPhail**
14:40	ACG-O-Tu-A10	SIMS analysis of particles in Aerogel	Richard J Chater
15:00	**ACG-I-Tu-A11**	**Investigation into the Nature of Historical Tapestries Using Time of Flight Secondary Ion Mass Spectrometry**	**Chris Carr**
15:40		Coffee	
16:00	ACG-O-Tu-A12	Measurement of Sulfur Isotope Ratios in Micrometer-Sized Samples by NanoSIMS	Baerbel Winterholler
16:20	ACG-O-Tu-A13	Basic Experiment of Remote SIMS Method for Lunar Surface Observation	Koji Tanaka
16:40	ACG-O-Tu-A14	Secondary Ionization Mass Spectrometric Analysis of Impurity Element Isotope Ratios in Nuclear Reactor Materials	David Gerlach
17:00	ACG-O-Tu-A15	Combined SIMS / SEM technique for environmental monitoring of nuclear facilities: detection, analysis, and characterization of radionuclides in microm	Laure Sangély
17:20	ACG-O-Tu-A16	Application of SIMS analyses on oxygen and hydrogen transport in SOFC materials	Natsuko Sakai
17:40	ACG-O-Tu-A17	Characterisation of irradiated nuclear fuel with SIMS	Lionel Desgranges
Session 4 – C2			
08:40	**ORG1-I-Tu-B01**	**SSIMS analysis of organics, polymer blends and interfaces**	**Lu-Tao Weng**
09:20	ORG1-O-Tu-B02	ToF-SSIMS analysis of plasma chemically deposited co-polymer films	Umut Oran
09:40	ORG1-O-Tu-B03	ToF-SIMS: Accurate Mass Scale Calibration	Felicia Green
10:00	ORG1-O-Tu-B04	Diffusion study of multi-organic layers in OLEDs by ToF SIMS	Yong-Chien Ling
10:20	ORG1-O-Tu-B05	3-D TOFSIMS Characterization of Black spots in Polymer Light Emitting diodes	Corrie Bulle-Lieuwma
10:40		Coffee	
11:00	**ORG1-I-Tu-B06**	**Interpretation of SIMS Spectra and Images using Careful Application of Multivariate Analysis**	**Matthew Wagner**
11:40	ORG1-O-Tu-B07	PCA of TOF-SIMS Spectra from Self-Assembled Monolayers: The affects of data normalization	Dan Graham
12:00	ORG1-O-Tu-B08	Simulation of SIMS for Polymers under the Assumption of Thermal Decomposition using QMD Method	N Kato
12:20	ORG1-O-Tu-B09	G-SIMS-FPM: The Full Picture - Combined Positive and Negative Ion Fragmentation Study	Ian Gilmore
12:40	ORG1-O-Tu-B10	SIMS Studies of Polymeric Tertiary Structure in Monolayers	Joseph A Gardella Jr
13:00		Lunch	
14:00	BIO1-O-Tu-B11	ToF-SIMS imaging as a tool to study the spatial behaviour of bioorganic surface components in brain tissue and single neuroblastoma cells	Maarten Altelaar
14:20	BIO1-O-Tu-B12	Direct NanoSIMS imaging of diffusible elements in surfaced block of cryo-processed biological samples	Philippe Hallégot
14:40	BIO1-O-Tu-B13	Imaging and differentiation of cellular responses to ionizing radiation by time-of-flight secondary ion mass spectrometry	Kaung J Wu

15:00	BIO1-O-Tu-B14	Introduction of a Cryosectioning-ToF-SIMS Instrument for Analyzes of Non-Dehydrated Biological Samples	Joerg Moeller
15:20	BIO1-O-Tu-B15	TOF-SIMS imaging of Chlorhexidine-digluconate transport in frozen hydrated biofilms of the fungus Candida Albicans	Bonnie Tyler
15:40		Coffee	
16:00	BIO1-O-Tu-B16	Investigating Lipid Interactions and the Process of Raft Formation in Cellular Membranes Using Model Membranes	Carolyn McQuaw
16:20	BIO1-O-Tu-B17	ToF-SIMS Studies of Bacillus Using Principal Component Analysis with Possible Identification and Taxonomic Applications	Charlotte Thompson
16:40	BIO1-O-Tu-B18	Bioforensics characterization of Bacillus spores using ToF-SIMS	John Cliff
17:00	BIO1-O-Tu-B19	Acquisition of Chemical Information from Cell Samples using TOF-SIMS Imaging	Birgit Hagenhoff
17:20	BIO1-O-Tu-B20	Development of SIMS as a Novel Investigative Tool for the Analysis of Cell Sheets and their Extracellular Matrix Proteins	David Castner
17:40	BIO1-O-Tu-B21	7.9 eV Single Photon Ionisation of Derivatized Peptides	Luke Hanley
Session 5 – C9			
08:40	CLU3-O-Tu-C01	The massive cluster probe in SIMS. Influence of the projectile size and of the energy on sputtering and desorption-ionisation from various solids	Serge Della-Negra
09:00	CLU3-O-Tu-C02	Coarse-Grained Molecular Dynamics Studies of Cluster-Bombarded Benzene Crystals	Edward Smiley
09:20	CLU3-O-Tu-C03	Topography Formation During C60+ Bombardment of Silicon	GregGillen
09:40	CLU3-O-Tu-C04	Fundamental Studies of Water Ice by Cluster Ion Bombardment	Christopher Szakal
10:00	CLU3-O-Tu-C05	Secondary ion emission from organic targets impacted with Gold projectiles of 1-500 atoms	Christelle Guillermier
10:20	CLU3-O-Tu-C06	Prospects and Challenges of Cluster SIMS	Jiro Matsuo
10:40		Coffee	
11:00	CLU3-O-Tu-C07	Comparison of TOF-SIMS and XPS Analysis Using a C60 Ion Beam	Noriaki Sanada,
11:20	CLU3-O-Tu-C08	XPS and UPS Analysis of PMMA Films Bombarded by keV C60+ Ions	Igor Bolotin
11:40	CLU3-O-Tu-C09	3D Molecular Imaging Using Cluster SIMS	Greg Gillen
12:00	CLU3-O-Tu-C10	SIMS Depth Profiling of Polymer Blends with Protein Based Drugs	Joseph A Gardella Jr
12:20	CLU3-O-Tu-C11	Depth Profiling of a Medical Device-copolymer using a C60+ Cluster Ion Source	Robert Braun
12:40	CLU3-O-Tu-C12	ToF/SIMS analysis of fluorocarbon-grafted PET with a gold cluster ion source	Michael Kelley
13:00		Lunch	
Wednesday 14th September			
Session 6 – C16			
08:40	**Plenary-We-A01**	**The contribution of mass spectrometry to the bio-sciences**	**Professor Simon Gaskell**
09:40	ORG2-O-We-A02	Suppression and enhancement of non-native molecules within biological systems	Emrys Jones
10:00	**ORG2-I-We-A03**	**Why MALDI works – From Hypotheses to Experimental Evidence**	**Michael Karas**

10:40		Coffee	
11:00	ORG2-O-We-A04	A Comparative Study of Secondary Ion Yield from Biological Membranes Using Au, Au3 and C60 Ion Beams	Matthew Baker
11:20	**ORG2-I-We-A05**	**Matrix-Enhanced Secondary Ion Mass Spectrometry**	**Arnaud Delcorte**
12:00	ORG2-O-We-A06	Matrix-Assisted Cluster SIMS	Jay Locklear
12:20	ORG2-O-We-A07	S-SIMS and MetA-SIMS study of organic additives in thin polymer coatings	Lesley Adriaensen
12:40	ORG2-O-We-A08	A new analysis of the depolymerised fragments of lignin polymer in the plant cell walls using ToF-SIMS	Kaori Saito
13:00		Lunch	
Session 7 – C2			
08:40	**Plenary-We-A01**	**The contribution of mass spectrometry to the bio-sciences**	**Professor Simon Gaskell**
09:40	**DEP1-I-We-B01**	**Depth Profiling for Emerging Semiconductor Materials**	**Paul Ronsheim**
10:20	DEP1-O-We-B02	Room Temperature Diffusion of Boron in Crystalline Si During SIMS Depth Profiling	Enrico Napolitani
10:40		Coffee	
11:00	DEP1-O-We-B03	An unexpected solution to the Na and Li depth profiling problem in oxides	Temel Büyüklimanli
11:20	DEP1-O-We-B04	SIMS quantitative depth profiling of matrix elements in semiconductor layers	Georgiy Guryanov
11:40	DEP1-O-We-B05	Depth Profiling of Ultrathin Films and Their Multilayers by DSIMS	Petr Babor
12:00	DEP1-O-We-B06	Shallow B depth profiling in Si without complete oxidation of the analytical area	Temel Büyüklimanli
12:20	DEP1-O-We-B07	SIMS depth profiling of Boron ultra shallow junctions using oblique O2+ beams down to 150eV	Marc Juhel
12:40	DEP1-O-We-B08	Cesium/Xenon dual beam depth profiling: nature of the sputtered atom and ionization probability	Jeremy Brison
13:00		Lunch	
Session 8 – C9			
08:40	**Plenary-We-A01**	**The contribution of mass spectrometry to the bio-sciences**	**Professor Simon Gaskell**
09:40	BTC-O-We-C01	The use of a desktop TOF-SIMS instrument in the field of biomedical surface modification	A John Eccles
10:00	BTC-O-We-C02	ToF-SIMS imaging of micropatterned proteins and cells	Dae W Moon
10:20	BTC-O-We-C03	Bioactive Molecules for Biomimetic Materials: Quantification of RGD Peptide Sequences by ToF-S-SIMS Analysis	Suzie Poulin
10:40		Coffee	
11:00	BTC-O-We-C04	Characterization of PNA Microarrays as a Function of Primary Ion Species	Sebastian Hellweg
11:20	BTC-O-We-C05	Direct ToF-SIMS Analysis of Thin Layer Chromatography Plates	Matthew R Linford
11:40	BTC-O-We-C06	Quantitative analysis of bio-surfaces using ToF-SIMS	Tae G Lee
12:00	BTC-O-We-C07	Nanoscale Surface of Carbon Nanotube Fibers for Medical Applications:	Stefanie Polizu
12:20	BTC-O-We-C08	ToF-SIMS imaging of gradient polyethylene surface with biofunctional groups	Dae W Moon
12:40	BTC-O-We-C09	Studies by imaging TOF-SIMS of bone mineralization on porous titanium implants after one week in bone	Cecilia Eriksson
13:00		Lunch	

Thursday 15th September			
Session 9 –C16			
08:40	**DIS-I-Th-A01**	**Molecule Specific Imaging and Analysis in Biology: What are the Challenges and The Important Applications**	**Andrew Ewing**
09:40	DIS-O-Th-A02	Why don't biologists use SIMS	Ron M A Heeren
	DIS-O-Th-A03	Improvements in SIMS continue. Is the end in sight?	Nicholas Winograd
	DIS-O-Th-A04	ToF-SIMS analysis of bio-systems – Are polyatomic primary ions the solution?	E A Jones
11:00		Coffee	
11:20	DIS-O-Th-A05	Information from Complexity: Challenges of ToF-SIMS Data Interpretation	David Castner
	DIS-O-Th-A06	Rapid discrimination of the casual agents of urinary tract infection using ToF-SIMS with chemometric cluster analysis	Roy Goodacre
	DIS-O-Th-A07	Multivariate Statistical Image Processing for Molecular Specific Imaging in Organic and Bio-systems	Bonnie Tyler
	DIS-O-Th-A08	Spatial Statistics and Interpolation Methods for TOF SIMS Imaging	Joseph Gardella
13:00		Lunch	
14:00	DIS-O-Th-A09	Quantitative imaging of cells with SIMS-Nanoautography with stable isopte tracers	Claude Lechene
	DIS-O-Th-A10	High resolution SIMS imaging of cations in mammalian cell mitosis, and in Drosophila polytene chromosomes	Riccardo Levi-Setti
	DIS-O-Th-A11	Specimen preparation and calibration for NanoSIMS analysis of biological materials	Chris Grovenor
	DIS-O-Th-A12	Cellular Localization of a 15n Labelled Peptidic Vector using Nanosims Imaging	Jean-Luc Guerquin-Kern
15:40		Coffee	
16:00	DIS-O-Th-A13	Label- and amplification-free genotyping of genomic DNA	Jőrg D Hoheisel
	DIS-O-Th-A14	Mass Spectrometric Characterization of Elements and Molecules in Cell Culture and Tissue	Heinrich Arlinghaus
	DIS-O-Th-A15	Quantitative analysis of biological membrane composition with high lateral resolution	Steven Boxer
	DIS-O-Th-A16	Imaging lipid distributions in model membranes with selectively deuterated components using Time of Flight Secondary Ion Mass Spectrometry (ToF-SIMS)	Mark Biesinger
	DIS-O-Th-A17	Localisation of lipids in freeze-dried mouse brain sections by imaging ToF-SIMS	Peter Sjövall
	DIS-O-Th-A18	Localization of Cholesterol in Rat Cerebellum with Imaging TOF-SIMS. Effect of tissue preparation	Håkan Nygren
Session 10 – C2			
08:40	**SEM-I-TH-B01**	**Characterizing High-K and Low-K Dielectric Materials for Semiconductors: Progress and Challenges**	**Joe Bennett**
09:20	SEM-O-Th-B02	Characterization of HfO2 dielectric films with low energy SIMS	Zhixiong (J) Jiang
09:40	SEM-O-Th-B03	SIMS Analysis for HfSiO(N) thin films	Shiro Miwa
10:00	SEM-O-Th-B04	Nitrogen profiling in high-k layers has much to gain from a combined TOFSIMS-Angle resolved XPS combined study	Thierry Conard
10:20	SEM-O-Th-B05	Back Side SIMS Analysis of Hafnium Silicate	Fred Stevie
10:40		Coffee	

11:00	SEM-O-Th-B06	HfSiO(N) composition depth profiling: can we get a quantitative answer using SIMS?	Thierry Conard
11:20	SEM-O-Th-B07	Quantitative Si Depth Profiling of HfxSiyO2 Using Normal Incidence Cs and ERD	Hans Maul
11:40	SEM-O-Th-B08	Dynamic SIMS Analysis of Low-k Dielectric Materials	Ian Mowat
12:00	SEM-O-Th-B09	ToF-SIMS and AFM studies of low-k dielectric etching in fluorocarbon plasmas	Paolo Lazzeri
12:20	**SEM-I-Th-B10**	**Ultrashallow depth profiling by using SIMS and Ion Scattering Spectroscopy**	**Yuji Kataoka**
13:00		Lunch	
14:00	**NAN-I-Th-B11**	**Static SIMS for analysis of molecular conformation and orientation**	**Patrick Bertrand**
14:40	NAN-O-Th-B12	Characterisation of electrospun nanowebs with Static SIMS	Pieter Van Royen
15:00	NAN-O-Th-B13	Towards Molecular Electronic Circuitry: Selective Deposition of Metals on Patterned Self-Assembled Monolayer Surfaces	Amy Walker
15:20	NAN-O-Th-B14	Particle-induced desorption from self-assembled monolayers: signatures of an intricate balance between inter- and intramolecular interactions	Peter Lievens
15:40		Coffee	
16:00	**PAR-I-Th-B15**	**SIMS of Nanoparticles**	**Klaus Wittmaack**
16:40	PAR-O-Th-B16	Examining Ion Sputtering of Nanoparticles and Nanoporous Materials	Daniel Gaspar
17:00	PAR-O-Th-B17	Characterization of Individual Atmospheric Aerosol Particles with TOF-SIMS	Richard Peterson
17:20	PAR-O-Th-B18	TOF-SIMS analysis of ultrafine carbon particles with a pulsed beam sputter mode	Wilfried Szymczak
17:40	PAR-O-Th-B19	Urban and rural aerosol particle characterisation by SIMS and SSMS compared with environmentally related children diseases	Piotr Konarski
Poster Session 2, 18:00 – 20:00 – C15/B1			
	DEP-P-Th-P01	Sodium and hydrogen analysis of room temperature glass corrosion using low energy Cs sims	Sarah Fearn
	DEP-P-Th-P02	Application of B-doped Si Multiple Delta-Layers for Calibration of SIMS Depth Scale	Kyung J Kim
	DEP-P-Th-P03	An Alternative Method of Using an Electron Beam for Charge Compensation During uleSIMS Experiments	Berta Guzman de la Mata
	DEP-P-Th-P04	Ultra Shallow SIMS Depth Profiling	Andrew Wee
	DEP-P-Th-P05	Narrow surface transient and high depth resolution SIMS using 250eV O2+	Ab Razak Chanbasha
	DEP-P-Th-P06	SIMS Depth Profiling of Rubber – Tyre Cord Bonding Layers prepared using 64Zn depleted ZnO	David E Sykes
	DEP-P-Th-P07	High Sensitive Analysis of Atmospheric Gas Elements	Shiro Miwa
	DEP-P-Th-P08	MEM-deconvolution analysis of ultra-shallow junction depth profiles	Mitsuhiro Tomita
	DEP-P-Th-P09	Calibrations of ToF-SIMS sputter rates in alumina scales formed on FeCrAl alloys	Josefin Engkvist
	DEP-P-Th-P10	Boron Ultra Low Energy SIMS Depth Profiling improved by Rotating Stage	Damiano Giubertoni
	DEP-P-Th-P11	Characterization of layers and interfaces during the silicide formation of CoSix and NiSiy	Uwe Breuer
	DEP-P-Th-P12	Deconvolution of SIMS Depth Profiles in the Presence of Beam Induced Roughness	Boubker Fares
	DEP-P-Th-P13	SIMS characterisation of superconductive MgB2 layers prepared by ion implantation and pulsed plasma treatment	Piotr Konarski
	DEP-P-Th-P14	Useful Yields and Depth Resolution in TOF-SIMS	Takahiro Hoshi

		Depth Profiling	
	DEP-P-Th-P15	Ultra-low energy O2+ sputtering for improved accuracy in SIMS depth profiles	Takahiro Hoshi
	DEP-P-Th-P16	ToF-SIMS Depth Profiling of (Ga,Mn)As Capped With Amorphous Arsenic: Effects of Annealing Time	Ulf Bexell
	DEP-P-Th-P17	Emission of “impurity-matrix” type dimers from GaX semiconductors (X = N, P, As, Sb).	Alex P Kovarsky
	SEM-P-Th-P18	Quantitative analysis of surface contaminants on silicon wafers by means of TOF-SIMS	Patrick Rostam-Khani
	SEM-P-Th-P19	Determination of the organic contaminations on Si wafer surfaces by static ToF-SIMS: improvement of the detection limit with C60+	Claude Poleunis
	SEM-P-Th-P20	Quantitative SIMS analysis of SiGe composition with low energy O2+ beams	Zhixiong X Jiang
	SEM-P-Th-P21	SIMS analysis of impurities and nitrogen isotopes in gallium nitride thin films	Hajime Haneda
	SEM-P-Th-P22	SIMS profiling of doped NiSi gates	Tom Janssens
	SEM-P-Th-P23	Study of SIMS ionization probabilities of different composition of In(AlxGa1-x)P	Junichiro Sameshima
	SEM-P-Th-P24	Profiles of boron and matrix elements through thin SiON layer	Junichiro Sameshima
	SEM-P-Th-P25	“Non-destructive” B, P and As Dosimetry Using Normal Incidence Oxygen	Hans-Ulrich Ehrke
	SEM-P-Th-P26	Determination of impurities and main elements in thin film structures InN/GaN on sapphire.	Alex P Kovarsky
	SEM-P-Th-P27	Characterization of Laser-Fired Contacts in PERC Solar Cells: SIMS and TEM Analysis Applying Advanced Preparation Techniques	Uwe Zastrow
	SEM-P-Th-P28	C60+ Cluster Beam Depth Profiling of Semiconductor Materials	Peter Chi
	SEM-P-Th-P29	Correlation of SIMS sputtering rate variations with primary beam current drifts: an effective application to high precision full wafer mapping	Marc Juhel
	SEM-P-Th-P30	Improving the growth of HfO2 ALD layers by modifying growth parameters and reducing precursors contaminants	Thierry Conard
	SEM-P-Th-P31	Measurements of Ti-Containing Barrier Materials and Low-K dielectric Films Using Backside Polishing SIMS	Ian Mowat
	SEM-P-Th-P32	Phosphorous degassing from Poly Silicon under thermal exposure: A ToF-SIMS depth profile investigation	Stefano G Alberici
	SEM-P-Th-P33	SIMS Analysis of Multiple Quantum Wells in a Vertical Cavity Surface Emitting Laser Structure Using the Mixing-Roughness-Information depth Model	Shinya Ootomo
	SEM-P-Th-P34	Thermal effects on 1H and 2H distributions in atomic layer deposition of HfO2 and Al2O3 using heavy water (D2O)	Philippe Holliger
	SEM-P-Th-P35	Investigations of LED Structure with Graded InxGa1-xP Buffer by SIMS Method	Andrej Vincze
	SEM-P-Th-P36	The influence of impurity profile on ultrashallow GaAs sidewall tunnel junction characteristics	Takeo Ohno
	SEM-P-Th-P37	Ultra low energy SIMS depth profiling of sub-2nm Silicon oxynitride films	Chris Mulcahy
	SEM-P-Th-P38	TOF-SIMS studies on Rose Bengal devices: Search for the mechanism responsible for resistive switching	Astrid Besmehn
	BIO2-P-Th-P39	Imaging of Human Liver Cell Intoxicated by Heavy Metal using Time-of-flight Secondary Ion Mass Spectrometry (TOF-SIMS)	Fu-Der Mai
	BIO2-P-Th-P40	Study of the mechanism of diatoms multiplication by means of 29Si isotope tracing	J-Nicolas Audinot

	BIO2-P-Th-P41	Quantitating MIMS Ratios Using Hue, Saturation, and Intensity Displays	Claude Lechene
	BIO2-P-Th-P42	High order of DNA replication identified in fibroblasts nuclei with Multi-Isotope Imaging Mass Spectrometry	Claude Lechene
	BIO2-P-Th-P43	Multi-isotope imaging mass spectrometry (MIMS) quantitative mapping of protein turnover in the bullfrog saccula	Claude Lechene
	BIO2-P-Th-P44	Tectorial Membrane Protein Turnover Revealed by Multi-isotope Imaging Mass Spectrometry	Claude Lechene
	BIO2-P-Th-P45	Multi-Isotope Imaging Mass Spectrometry of Larval Zebrafish for Studying Acute Renal Failure	Claude Lechene
	BIO2-P-Th-P46	Determination of Steady State Cs+ Implantation in Biological Samples	Claude Lechene
	BIO2-P-Th-P47	Stable isotopes for individual cell retrieval after transplantation	Claude Lechene
	BIO2-P-Th-P48	The analysis of boron in the human glyoma graft by dyanamic secondary ion mass spectrometry(SIMS)	Toshiko Yoshida
	BIO2-P-Th-P49	Bioaccumulation of chromium in aquatic macrophyte Borreria scabiosoides Cham. & Schltdl.	Konstantin Gavrilov
	NAN-P-Th-P50	Atomic distribution in quantum dots- a ToF SIMS study	Yong-Chien Ling
	NAN-P-Th-P51	The lateral resolution of ToF-SIMS analysed by means of an advanced nanoscale strip-pattern	Wolfgang Unger
	PAR-P-Th-P52	Analysis of Volatile Nanoparticles Emitted from Diesel Engine using Tof-Sims and Silver Deposition / Tof-Sims	Masae Inoue
	PAR-P-Th-P53	Quantitative characterizations of styrene-butadiene core-shell latexes by TOF-SIMS and Pyrolysis GC/MS	Toshihiko Maekawa
	PAR-P-Th-P54	Characterization of individual complex particles in urban atmospheric environment	Kenichiro Suzuki
	PAR-P-Th-P55	TOF-SIMS measurements of the exhaust particles emitted from gasoline and diesel engine vehicles	Bunbunoshin Tomiyasu
	PAR-P-Th-P56	Depth profile of coated hollow spheres	Andrej Oriňák
	ORG2-P-Th-P57	Surface Chemical Analysis of Thermally Degraded Cotton	R Mitchell
	ORG2-P-Th-P58	Secondary Ion Statistics and Determination of Nanocluster (m > 10^7 amu) Ion Registration Efficiency.	Andrey V Novikov
	ORG2-P-Th-P59	Towards a Fully Optimised Organic LED Device: Analysis of Surface Synthesis Using Coupling Reactions by ToF-SIMS	Rosella Pinna
	ORG2-P-Th-P60	G-SIMS of Thermosetting Polymers	Philip N Hawtin
	ORG2-P-Th-P61	Quantitative and High Mass ToF-SIMS Studies of Siloxane Segregation in Hydrogel Polymers Using Cryogenic Sample Handling Techniques	Joseph A Gardella Jr
	ORG2-P-Th-P62	Identification of Hydrocarbon Contamination in Mass Spectra	Nikolai L Yakovlev
	ORG2-P-Th-P63	Effect of dilute acrylic acid vapour on lubricated recording hard-disk media surfaces	Rong Ji
	ORG2-P-Th-P64	ToF-SIMS analysis of model nuclear waste glasses	Sandra Ristori
	ORG2-P-Th-P65	ToF-SIMS as a reliable tool for carotenoids and chlorophyll detection in natural samples: fruits, flowers and microalgae	Laurent Houssiau
	ORG2-P-Th-P66	Using Time-of-Flight Secondary Ion Mass Spectrometry to Investigate Reaction, Destruction, Penetration and Aggregation of Vapor-Deposited Metal Atoms	Zihua Zhu
	ORG2-P-Th-P67	Depth Profile Analysis of OLED Devices Using TOF-SIMS with Gradient Shaving Preparation	Takahiro Shibamori

	ORG2-P-Th-P68	ToF-SIMS: Going Beyond Surface Chemical Composition	Kathryn Lloyd
	ORG2-P-Th-P69	Selective Detection of Organic Compounds on Modified Polymer Surfaces Using TOF-SIMS in Combination with Derivatization	Yeonhee Lee
	ORG2-P-Th-P70	Surface Spectroscopic Imaging of PEG-PLA Tissue Engineering Constructs With ToF-SIMS	Frank J M Rutten
	MAT-P-Th-P71	Characterization of the 3D-distribution of impurities in InP semiconductor using SIMS	Seyed Hassan Haji Hosseini Gazestani
	MAT-P-Th-P72	TOFSIMS Analysis of SiC-Cu Composites for Thermal Management Applications	Rolf Treichler
	MAT-P-Th-P73	NanoSIMS analysis of Ca doping at a grain boundary in a superconducting YBCO Ca-123/123 bicrystal	Chris R M Grovenor
	MAT-P-Th-P74	Selective oxidation of Fe-1.5Mn alloys: quantitative description of annealed surfaces	Didier Loison
	INS-P-Th-P75	SIMS Analysis using a new Noble Sample Stage	Shiro Miwaa
	INS-P-Th-P76	The "second life" of Cameca cesium ionizer	Yuriy Kudriavtsev
	INS-P-Th-P77	Caesium Sputter Ion Source Compatible	Sergey Belykh
	INS-P-Th-P78	Recent Developments and Applications of CAMECA Quadrupole SIMS Tools	Hans-Ulrich Ehrke
	INS-P-Th-P79	Improved automation system for the CAMECA IMS 7f.	Paula Peres
	INS-P-Th-P80	Development and characterisation of the new NanoSIMS 50L	Francois Horréard
20:00		Manufacturers' Users Meetings	
Friday 16th September			
Session 11 – C16			
09:00	DEP2-O-Fr-A01	Comparison between the SIMS and MEIS Techniques for the characterisation of ultra shallow Arsenic implants	Damiano Giubertoni
09:20	DEP2-O-Fr-A02	Collaborative SIMS Study and Simulations of Implanted Dopants in Si	Nikolai L Yakovlev
09:40	DEP2-O-Fr-A03	On the limitations of closely spaced delta layers for the assessment of various parameters in sputter profiling	Mark Dowsett
10:00	DEP2-O-Fr-A04	Secondary ion measurements for oxygen cluster ion SIMS	Satoshi Ninomiya
10:20	DEP2-O-Fr-A05	Surface oxidation during O2+ bombardment of Si:	Tom Janssens
10:40		Coffee	
11:00	DEP2-O-Fr-A06	Correlation between the ionization probability of Si and Ge and the Cs surface concentration	Ping Chen
11:20	DEP2-O-Fr-A07	SIMS evaluation of the compositional properties and layer integrity of GaNAs superlattices	Chris Mulcahy
11:40	DEP2-O-Fr-A08	Shave-Off Depth Profiling by the Nano Beam Sims	Masashi Nojima
12:00	DEP2-O-Fr-A09	Different optical conductivity enhancement (OCE) protocols to eliminate charging during ultra low energy SIMS profiling of semiconductor and semi insulating materials	Richard J H Morris
12:20	DEP2-O-Fr-A10	Diffusion in Lithium Niobate Wafers	Kamal K Soni
12:40	DEP2-O-Fr-A11	SIMS Depth Profiling of Deuterium Labeled Polymers in Polymer Multilayers	Fred A Stevie
13:00		Closing Address	
13:15		Lunch	
Session 12 – C2			
09:00	**ORG3-I-Fr-B01**	**Mutual Information Theory for Biomedical Applications**	**Satoka Aoyagi**
09:40	ORG3-O-Fr-	Characterisation of human hair by means of static	Claude Poleunis

	B02	ToF-SIMS: a comparison between Ga+ and C60+ primary ion	
10:00	ORG3-O-Fr-B03	SIMS Analysis of Biological Materials Using Cluster Ion Sources	Birgit Hagenhoff
10:20	ORG3-O-Fr-B04	A complete cryo-chain for the combined SIMS and SEM-EDXA analysis of physiologically relevant elements in biomedical samples	Walter H Schroeder
10:40		Coffee	
11:00	BIO2-O-Fr-B05	Submicron-scale coccolith chemistry revealed by nanoSIMS	Mathew R Kilburn
11:20	BIO2-O-Fr-B06	Molecular Specificity of CN- Secondary Ion Formation using Multi-Isotope Imaging Mass Spectrometry	Claude Lechene
11:40	BIO2-O-Fr-B07	Cations in mammalian cells and chromosomes: Elemental abundances by SIMS affected by sample preparation protocols	Konstantin L Gavrilov
12:00	BIO2-O-Fr-B08	Multi-Isotope Imaging Mass Spectrometry (MIMS) of a Nitrogen-Fixing Bacterium	Claude Lechene
12:20	BIO2-O-Fr-B09	Specific Mg2+ and Ca2+ binding at Heterochromatic DNA Giemsa bands and their Evolutionary Role in Chromosomal Structure	Riccardo Levi-Setti
12:40	BIO2-O-Fr-B10	Zinc ion image and measurements for concentration of the islet of Langerhans	Motonori Okabe
13:15		Lunch	
Session 13 – C9			
09:40	INS-O-Fr-C01	Implementing a SIMS ion source on the NRL Trace Element Accelerator Mass Spectrometer	David L Knies
10:00	INS-O-Fr-C02	Isotope Ratio Measurement with an Electrometer Array on the Cameca IMS nf	Peter Williams
10:20	INS-O-Fr-C03	The Development of a Range of C60 Ion Beam Systems	Rowland Hill
10:40		Coffee	
11:00	INS-O-Fr-C04	Development of a TOF version of the desktop MiniSIMS utilising a continuous primary ion beam	A John Eccles
11:20	INS-O-Fr-C05	Application of the Hadamard Transform to ToF-SIMS	Albert Fahey
11:40	MAT-O-Fr-C06	Imaging of oxide structures and reaction pathways	Charles A Mims
12:00	MAT-O-Fr-C07	Study of the carbon distribution in multi-phase steels using the NanoSIMS 50.	Nathalie Valle
12:20	MAT-O-Fr-C08	TOF-SIMS study of photocatalytic decomposition reactions on nanocrystalline TiO2 films	Hubert Gnaser
12:40	MAT-O-Fr-C09	TOF-SIMS study of paper surface coated with ZnO nanoparticles	Yong-Chien Ling
13:15		Lunch	